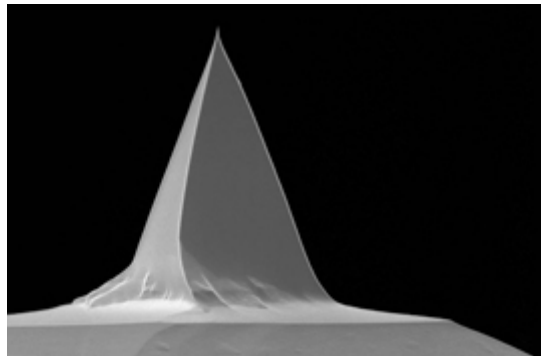


ANSCM-PC

ANSCM-PC probes are contact mode probes designed for Electronic Force Microscopy applications. These probes are coated on the reflex and tip sides with a thin layer of Pt-Ir, which allows for high resolution imaging.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** 1.5-3.0
- **ROC (nm) :** 30
- **Coating:** Pt/Ir, 25 nm \pm 5



[ANSCM-PC](#)

[On click zoom images](#)

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Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : Pt/Ir, 25 nm \pm 5

Parameter	Nominal	Min	Max
k (N/m)	0.2	0.1	0.6
f (kHz)	12.0	11.0	18.0
Length (μm)	450.0	440.0	460.0
Width (μm)	40.0	35.0	45.0
Thickness (μm)	2.50	2.00	3.00